Se	arcn	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/601,534	LABS ET AL.	
Examiner	Art Unit	
Kerri M. Rose	2616	

SEARCHED			
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
East - se	e printout	4/23/2007	KMR

SEARCH NOT (INCLUDING SEARCH))
	DATE	EXMR
370/206-208, 503, 509, 514, 517, 520 (text only - see printout) and IEEE	4/2/2007	KMR
375/354, 355, 359, 362, 365, 366, 371 (text only - see printout)	4/3/2007	KMR
combined citation search: 2004/0264510; 6,385,232; 6,493,360	4/18/2007	KMR
.Consult with Chau Nguyen (2616)	4/16/2007	KMR
Consult with David Payne (2611)	4/18/2007	KMR
375/353-376, 343, 260 (text only - see printout)	4/23/2007	KMR